Journal of MATERIALS RESEARCH

Ion-beam sputter deposition process for $Y_1Ba_2Cu_3O_{7-\delta}$ thin-film structures

J-P. Krumme, V. Doormann, F. Welz, and O. Dösssel Philips GmbH Forschungslaboratorien, Forschungsabteilung Technische Systeme Hamburg, Röntgenstrasse 24-26, D-22335 Hamburg, Germany

H. van Hal

Philips Research, Natuurkundig Laboratorium, P.O. Box 80000, NL-5600 JA Eindhoven, The Netherlands

(Received 21 April 1994; accepted 5 July 1994)

Ion-beam sputter deposition (IBS) has been developed to a fully oxygen-compatible technology for growth of complex oxides, such as $Y_1Ba_2Cu_3O_{7-\delta}$ (YBCO) thin films. The IBS system consists of an rf-plasma ion source with molybdenum grids for sputtering, a dc-plasma electron source for space charge compensation, stoichiometric YBCO and NGO targets, a beam chopper with BaO₂, Cu, and Nd blades for stoichiometry control, and an ECR-oxygen-plasma source for *in situ* film oxidation and photoresist removal. Due to its complexity the IBS process is fully computer-controlled. A salient feature of IBS is the excellent crystallographic and morphological properties of thin (100)/(010)- and (103)-oriented YBCO films on SrTiO₃ (STO) and NdGaO₃ (NGO) substrates. Sharp interfaces and good superconducting properties render this technology feasible for the fabrication of SIS-ramp-junction SQUID's.

Keywords: Physical vapor deposition (PVD); Superconductors; Thin film Materials: $YBa_2Cu_3O_{7-x}$

J. Mater. Res., Vol. 9, No. 11, p. 2747. © 1996 Materials Research Society